



THE AMERICAN ASSOCIATION FOR
LABORATORY ACCREDITATION

ACCREDITED LABORATORY

A2LA has accredited

CONTECH RESEARCH INC.

Attleboro, MA

for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General Requirements for the Competence of Testing and Calibration Laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated 18 June 2005*).



Presented this 20th day of February 2008.

A handwritten signature in cursive script, appearing to read "Peter Abney".

President

For the Accreditation Council

Certificate Number 1478.02

Valid to February 28, 2010

For the tests or types of tests to which this accreditation applies,
please refer to the laboratory's Electrical Scope of Accreditation.

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

CONTECH RESEARCH INC.
67 Mechanic Street
Attleboro, MA 02703
Mark Gates 508 226 4800

ELECTRICAL

Valid To: February 28, 2010

Certificate Number: 1478.02

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following tests on aerospace, aircraft, automotive, and computer components, cable assemblies, connectors and interconnect systems; commercial and military:

<u>Test</u>	<u>Test Method(s)</u>
Resistance Parameters	1 ma to 100ma @ 20mv DC OC 1 ma to 600 ADC
LLCR Manual, Semi-Automatic and Automatic	EIA 364 TP 23 MIL-STD-1344 Method 3002 MIL-STD-55302 IEC 512 Test 2a USB 2.0 SAE/USCAR-2 SAE/USCAR-30 IEEE 1394
Contact Resistance	EIA 363 TP 06 MIL-STD-1344 Method 3004 MIL-STD-202 Method 307 IEC 512 Test 2b IEEE 1394
Voltage Drop	SAE/USCAR-2
RF Parameters	300 KHz to 6 GHz @ 50 Ω 300 KHz to 2 GHz @ 75 Ω DC to 20 GHz, 1 ps
VSWR	EIA 364 TP 108 IEC 512 Test 25e
Attenuation	EIA 364 TP 101 IEC 512 Test 25b USB 2.0 SAE/USCAR-30 IEEE 1394

Propagation Delay	EIA 364 TP 103 IEC 512 Test 25d USB 2.0 SAE/USCAR-30 IEEE 1394
Crosstalk	EIA 364 TP 90 IEC 512 Test 25a IEEE 1394
Risetime Degredation	EIA 364 TP 102 IEC 512 Test 25c
RF Hi Pot Withstanding Voltage	MIL-PRF-39012
Impedance	EIA 364 TP 108 IEC 512 Test 25e USB 2.0 SAE/USCAR-30 IEEE 1394
Parameters	1 KHz to 1 GHz
Inductance	EIA 364 TP 33 & TP 69
Capacitance	EIA 364 TP 30 MIL-STD-202 Method 305 IEC 512 Test 22a USB 2.0
Detection Parameters	1ns, 10 ns, 50ns, .1µs, 1 µs, 10µs
Low Nanosecond Detection	EIA 364 TP 87
Discontinuity Detection	EIA 364 TP46 MIL-STD-202 Method 310 IEC 512 Test 2e IEEE 1394
DWV Parameters	300 V to 5000 VAC, to 4 mbars
DWV Sea Level	EIA364 TP 20A MIL-STD-1344 Method 3001 MIL-STD-202 Method 301 UL 1977 IEC 512 Test 4a USB 2.0 IEEE 1394
DWV. Altitude	EIA 364 TP 20A IEC 512 Test 4a

IR Parameters	100 VDC to 1000 VDC, 50,000 Megohms Max
Insulation Resistance	EIA 364 TP 21 MIL-STD-1344 Method 3003 MIL-STD-202 Method 302 IEC 512 Test 3a USB 2.0 SAE/USCAR-2 SAE/USCAR-30 IEEE 1394
Parameters	100 mA to 600ADC
Current Cycling.	EIA 364 TP 55 IEC 512 Test 9e SAE/USCAR-2
Temperature Rise	EIA 364 TP 70 UL1977 IEC 512 Test 5a/5b SAE/USCAR-2
Parameters	100 mA to 600ADC, 1V to 100 VDC
Current Overload (Hot Swap)	UL 1977
Resistance to Arcing	UL 1977

*Also customer specific test methods utilizing any combination of test equipment parameters listed above.